## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Prior Group Art Unit: 2858
Prior Examiner: J. Hollington

In Re NEW PATENT APPLICATION Of:

Applicant: Mikio OHTAKI

Appln. No.: To Be Assigned

Divisional Appl. of 09/434,490

Filed: July 16, 2001

For: SEMICONDUCTOR DEVICE

TEST APPARATUS

Atty Ref.: KAN 120D1

July 16, 2001

PRELIMINARY AMENDMENT

Commissioner for Patents Washington, D.C. 20231

Sir:

Preliminary to examination, please amend the application as follows:

## IN THE TITLE

Please change the title to -- SEMICONDUCTOR DEVICE TEST METHOD--

## IN THE SPECIFICATION

Page 1, before line 1, insert --This is a Divisional of Applicant's copending Application Serial No. 09/434,490.--

8-0003